



Avalanche Photodiodes at ESRF

Instrument Support Group,
Experiments Division

APD History:

At ESRF, ~50 NaI, YAP -PMT scintillation counters for diffraction, scattering and beam monitoring applications

These are limited to $<10^5 \dots 10^6$ cps,

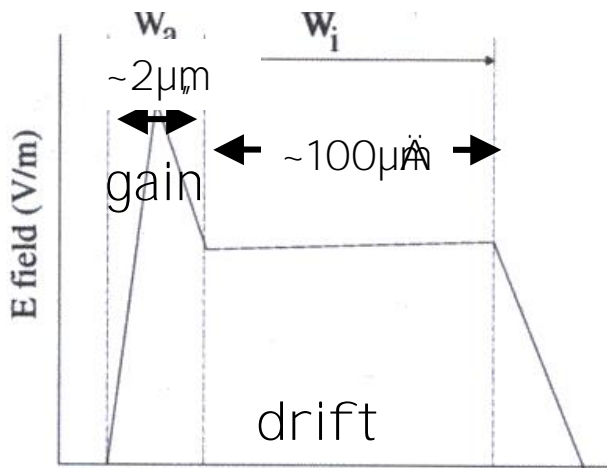
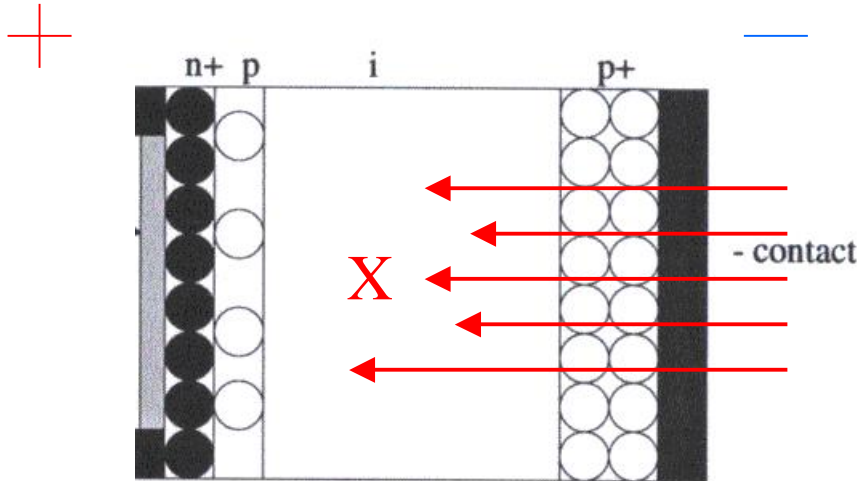
WIDESPREAD DEMAND FOR A FASTER COUNTER

Silicon APDs used since ~1993 (A. Baron et al.) for Mossbauer experiments with $<$ nanosec timing resolution

!! Could also be used as a fast counter ($> 10^7$ cps), but devices difficult/impossible to use for non-specialist users:

- array of NIM modules,
- need for fast oscilloscope
- sensitive manual adjustments (HT bias, etc...)

"Reach-through" avalanche photodiode*



Extremely robust devices

Thin , high field, 'dead layer'
p+ entrance

Available commercially
(infrared ranging market)

number of electron-hole pairs
for a 5.9keV photon is =
 $5900/3.62 = 1630$

Charge collected in ~1ns, gives
a current pulse ~260nA, or
13µV into a 500' load !!

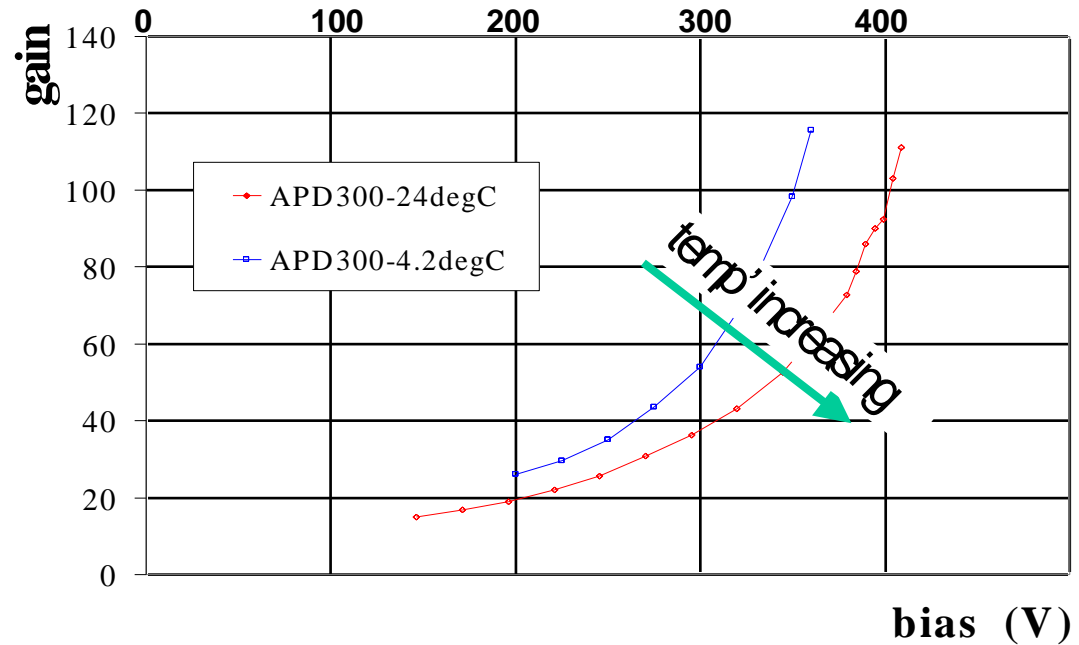
'white' amplifier noise too high
for a fast counter (~500MHz
bandwidth)

=> need detector 'internal gain'
3

*see Webb, McIntyre, Conradi RCA Rev 35 1974

APD Gain...

Perkin Elmer 5*5mm²
C30626 APD



For hard X ray detection, APD is used in semi-proportional gain mode, NOT as an avalanche counter

=> energy resolution possible

Gain

- increases logarithmically with voltage bias

- decreases with rising temperature

For constant gain, need compensation $\Delta V = 1.33\% / ^\circ\text{C}$ (gain = 100)

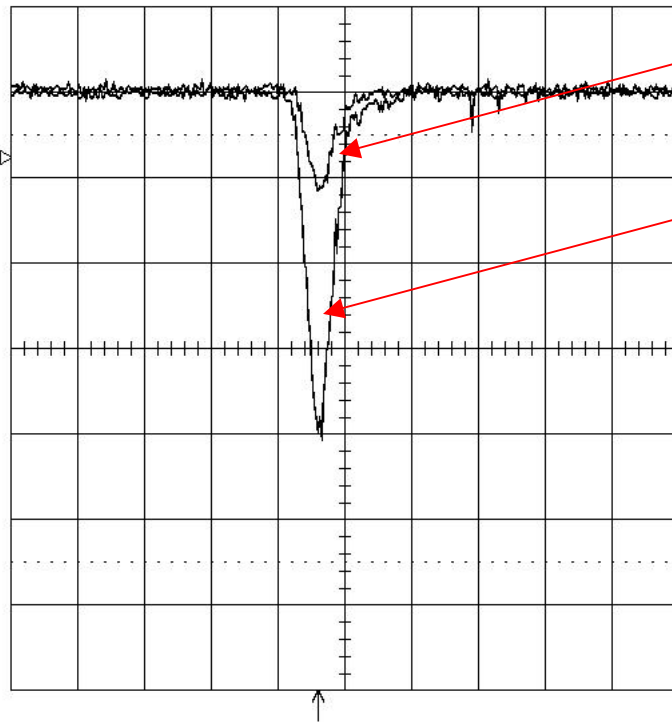
$\Delta V = 0.65\% / ^\circ\text{C}$ (gain = 20)

...and 'Speed'

31-Jul-02
16:13:09

5 ns
100 mV

M1
5 ns
100 mV



preamp signal output

Fe-55 (5.9keV)

and

Cd-109 (22.4keV)

Single X-ray pulses

gain ratio ≈ 4 'correct'

FWHM of pulses ≈ 3 ns

5 ns RIS

1 .1 V 50 Ω
2 5 V DC $\times 10$
3 .5 V 50 Ω $\times 10$
4 .5 V 50 Ω



1 DC -76 mV

10 GS/s

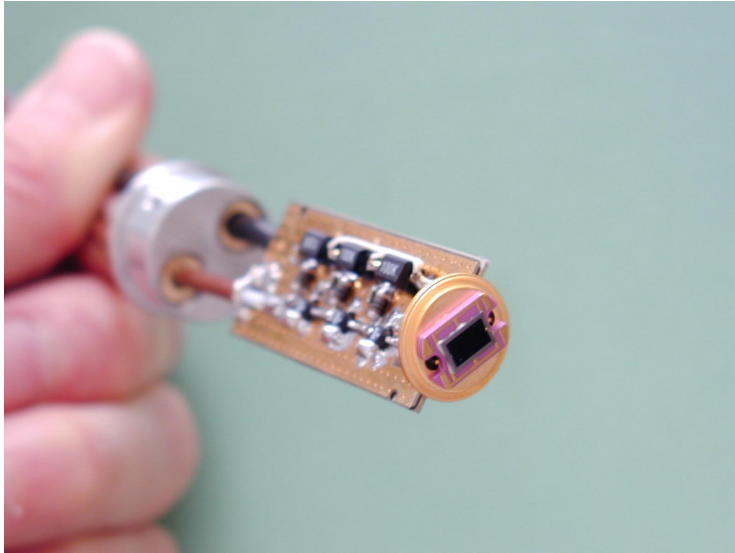
STOPPED

Specifications for a fast Silicon Avalanche Photodiode counter:

- Energy range < 3 keV (preamp noise threshold limit)
up to Si absorption limit ~ 30keV ✓
- Counting rate > 10^7 cps ✓
- Time resolution < 1ns (silicon interaction depth-drift time limit) ✓
- Dark noise < 0.1 cps ✓
- Energy resolution ~ 20 %
(separate of fluorescence and elastic scatter) [✓]
- EASY TO USE, COMPLETE HARD- SOFTWARE SYSTEM ✓
- AVAILABLE TO ALL USERS AT AT ESRF AND BEYOND [✓]
(36 APD heads and 26 ACE modules)

ESRF APD system

APD head /preamplifier



Hamamatsu $5 \times 3 \text{ mm}^2$
thickness $135 \mu\text{m}$
(absorption 45% at 12 keV)

or

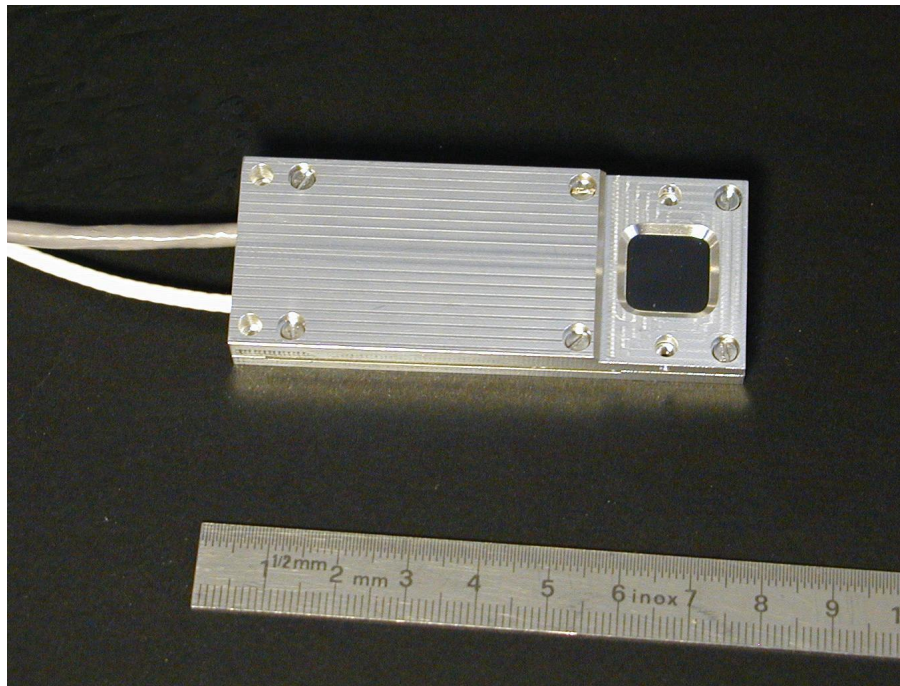
Perkin-Elmer 5×5 and $10 \times 10 \text{ mm}^2$
thickness $110 \mu\text{m}$ ($215 \mu\text{m}$)

Controller, timer-scaler, power supply



ESRF Heads

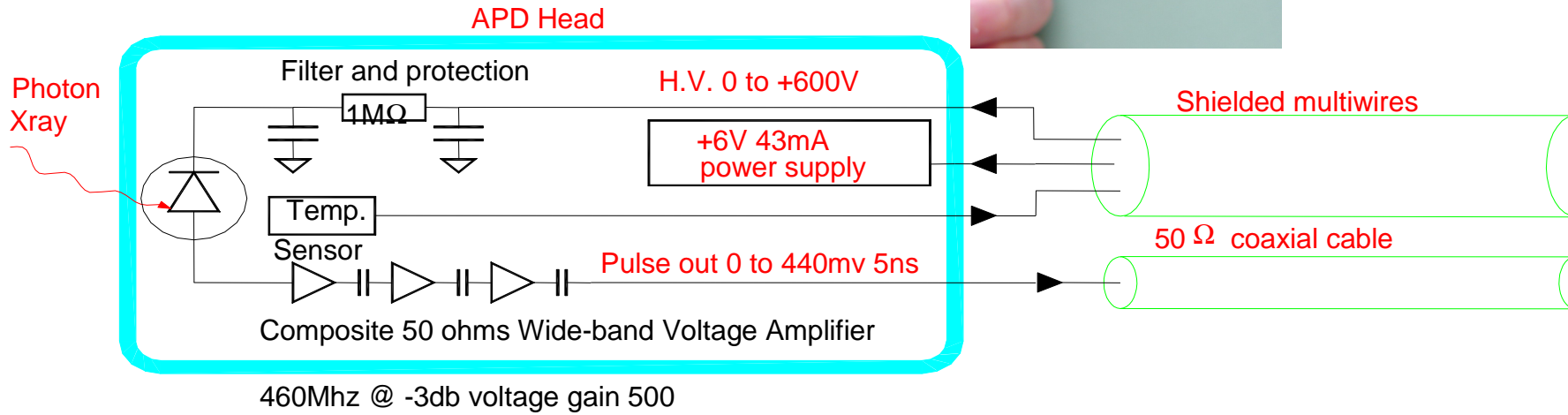
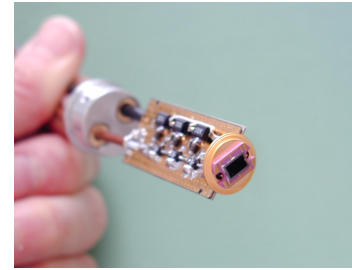
Pekin-Elmer 10*10mm²
thickness 110μm (215μm)
Transmission mode



Hamamatsu 5*3mm²
thickness 135μm
(absorption 45% at 12 keV)
and Perkin-Elmer 5*5
thickness 110um

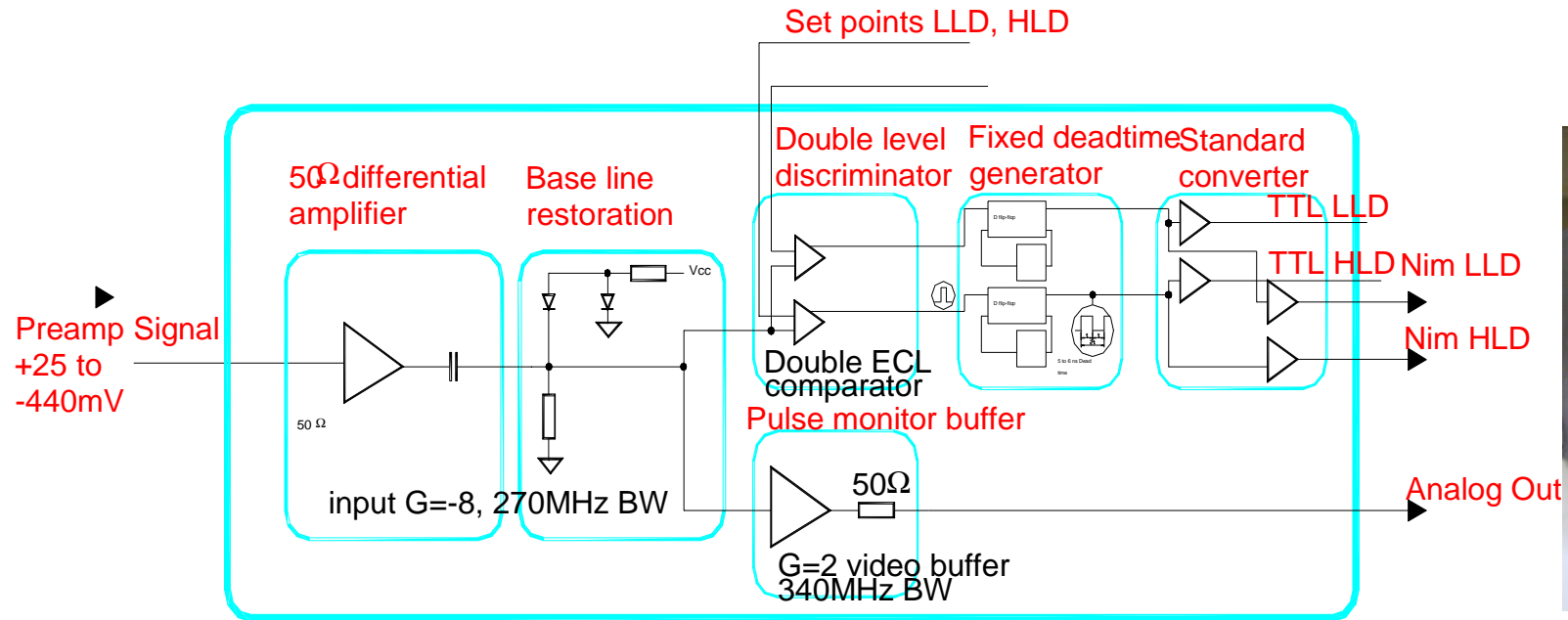


Head = APD + Pre-amplifier



- Low noise 3 stage amplifier mmic (Agilent) ~ 500MHz BW
- Thermally stable (temperature feedback stabilization possible)
- Compact (<300mW)
- Compatible with Perkin-Elmer and Hamamatsu APDs (15... 120pF)
- STABLE AGAINST OSCILLATION !!

APD Controller Electronics NI M unit: signal processing



Base line restoration to remove AC coupling offsets.

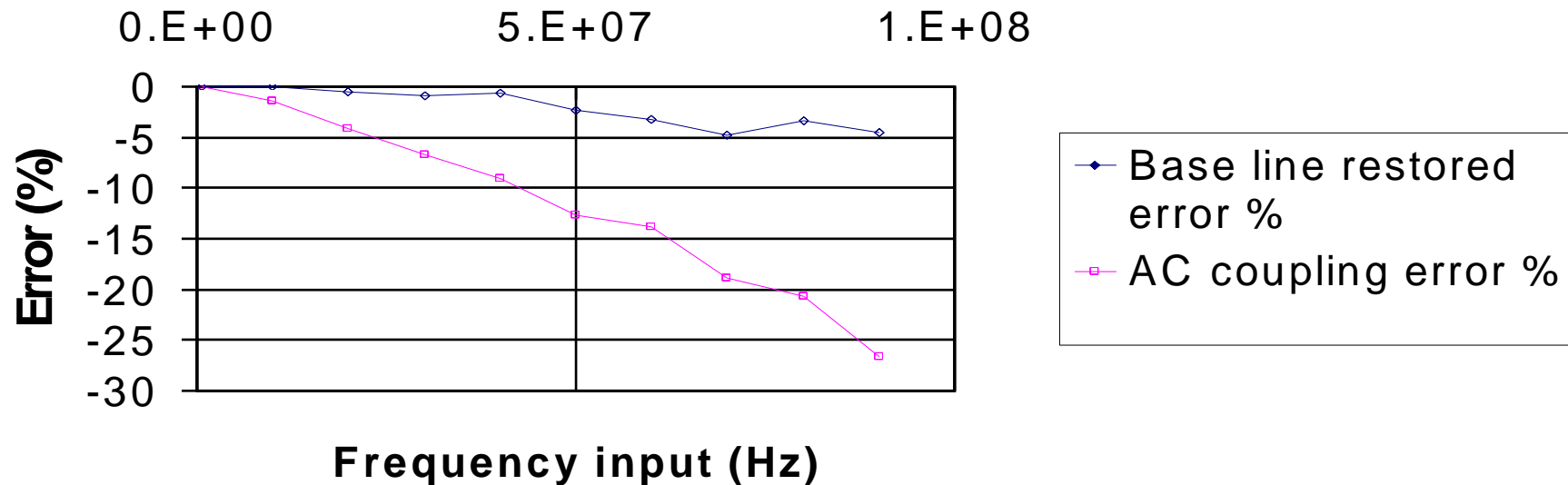
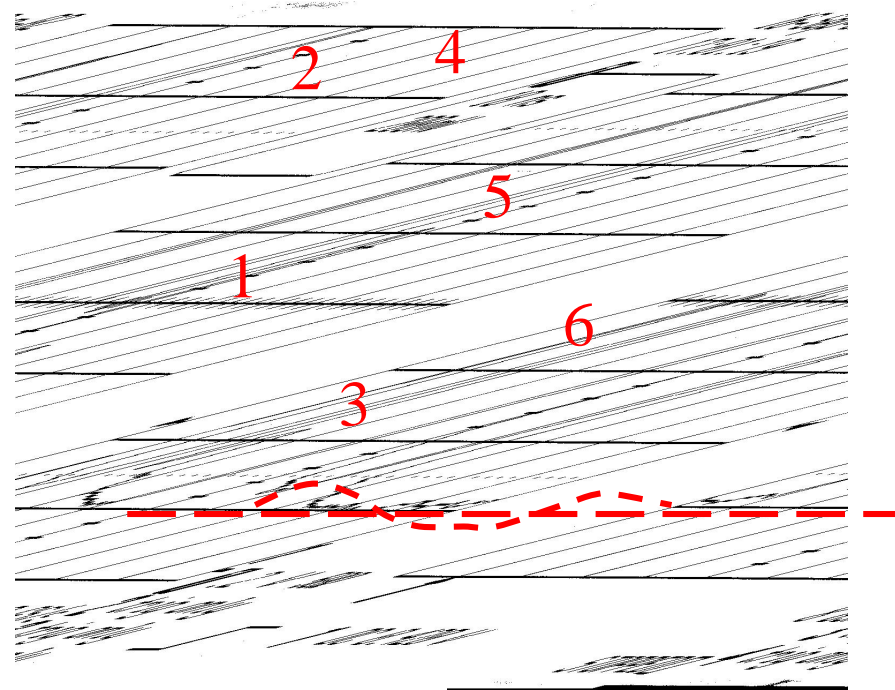
Double (window) discriminators

Fixed dead time generator.

Pulse Pile-up and base line restoration

RF preamp stages are a-c coupled, so 'average baseline' evolves with X-ray count rate

Schottky diode (non-linear) baseline restorer:

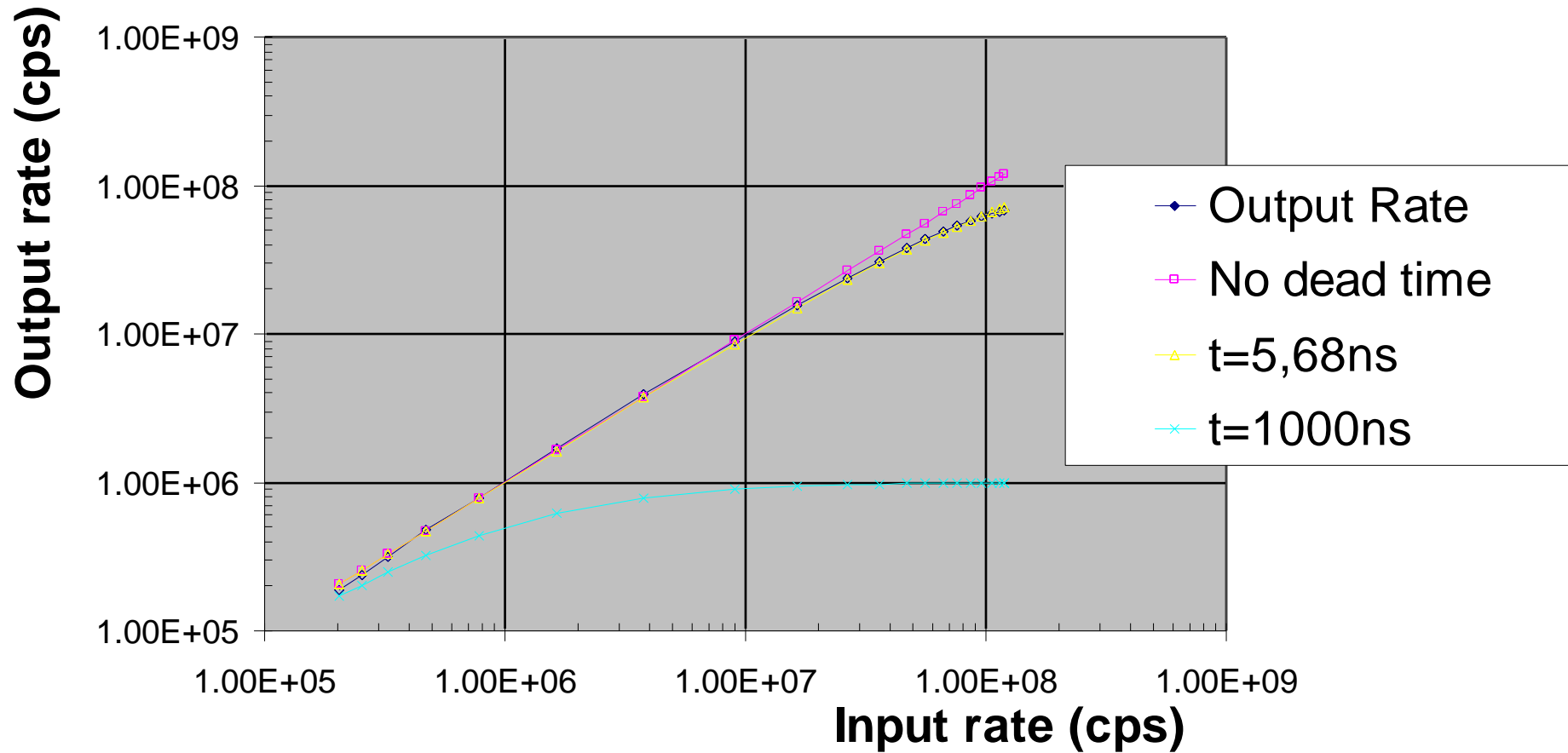


ACE (APD Controller Electronics) NI M unit

- Internal counter, 100MHz (180MHz / 10 pulse burst rate)
- External event synchronization : Trigger and gate input-output, direct SCA outputs (TTL and NI M)
- Energy Spectrum inspection by DAC controlled window discriminator scan
- bias current measurement for count saturation indicator and overload safety-- passive load plus HV feedback adjust
- Local control/display by graphic LCD with touch panel.
- Beamline remote control and data acquisition ('SPEC' software) via RS232/422 or GPI B.

(APD temperature measurement for gain compensation and device safety)

ESRF APD System: Count rate performance

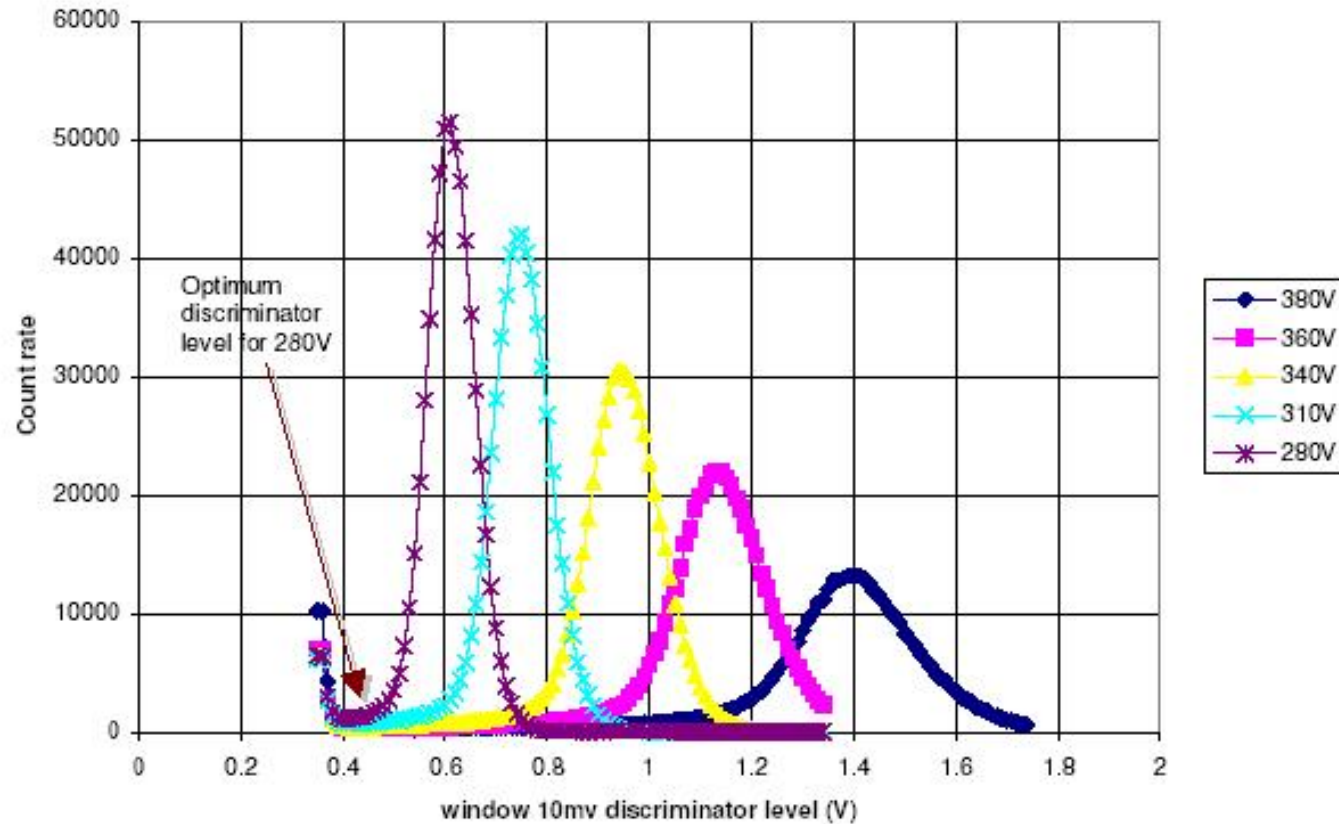


ESRF uniform fill mode I D2 beamline tests at 12.5 keV

Hamamatsu $5 \times 3 \text{mm}^2$ APD, nonparalyzable model fit

Energy resolution vs Gain

APD EGG 5x5 110um No1 Source Fe55



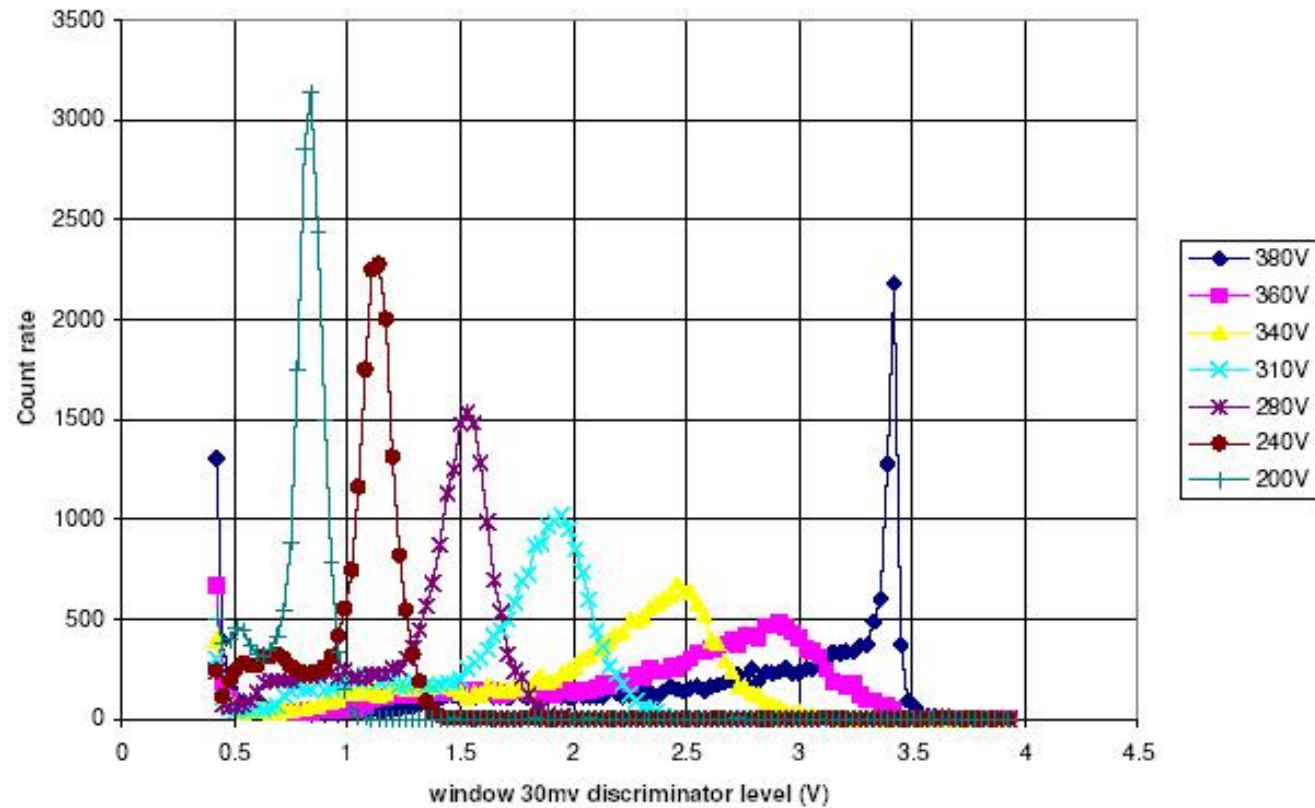
Fe-

The energy resolution (FWHM) versus bias voltage is:
Bias = 380V Energy resolution = 21% (optimal value for 6Kev)
Bias = 360V Energy resolution = 21.5%
Bias = 340V Energy resolution = 21.6%
Bias = 310V Energy resolution = 22.7%
Bias = 280V Energy resolution = 27%

Energy resolution vs Gain

APD EGG 5x5 110u No 1 Source Cd109

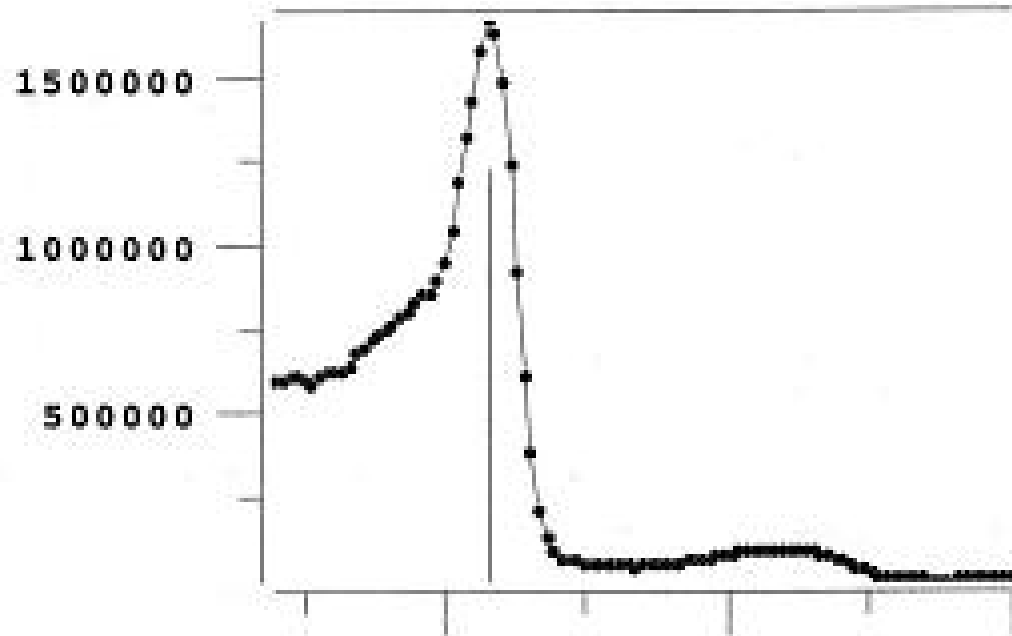
(bis)



Cd-109 22/25keV

The energy resolution (FWHM) versus bias voltage is:
Bias = 380V Energy resolution = no measurement (saturation of input)
Bias = 360V Energy resolution = 26.6%
Bias = 340V Energy resolution = 24%
Bias = 310V Energy resolution = 22%
Bias = 280V Energy resolution = 18.5%
Bias = 240V Energy resolution = 17% (optimal value for 22Kev)
Bias = 200V Energy resolution = 20%

Energy resolution vs. (Output) Count Rate



ACE window mode SCA scan, 52Mcps OCR

energy resolution ($E = 12.5\text{keV}$): $\Delta E/E = 39\%$

(Peak energy shift $\Delta V/V = -8\%$)

Commercialisation

-Licensing agreement between ESRF and Cyberstar (Oxford Danfysik catalogue distribution)

- NSLS (Brookhaven) basic NI M module, also produced by Cyberstar for Oxford Danfysik

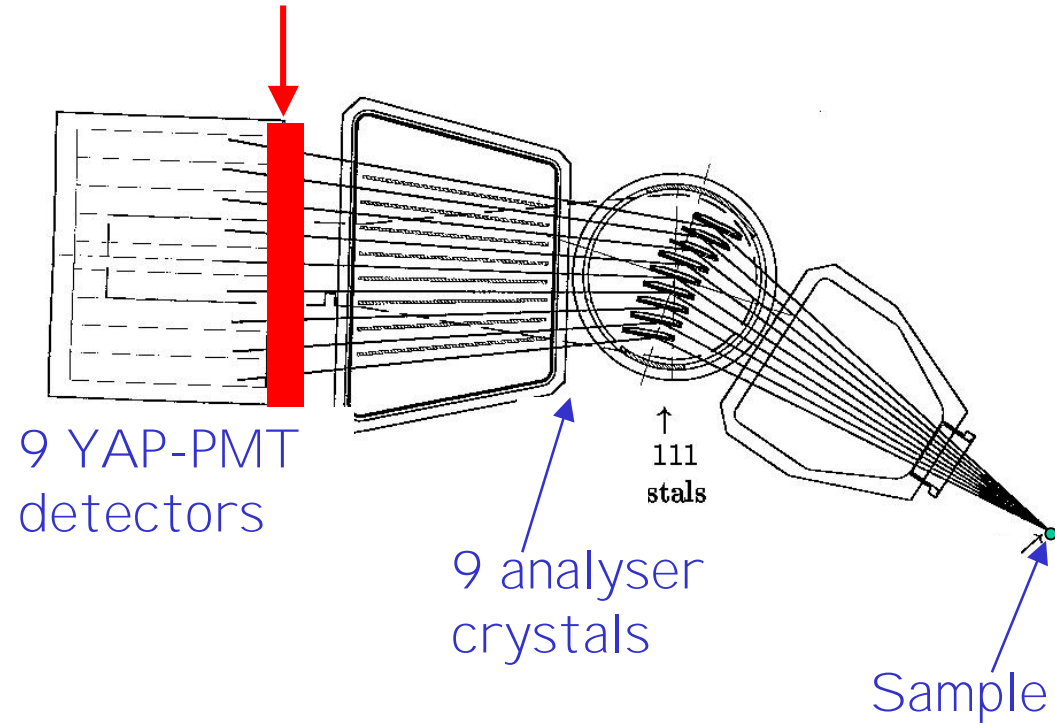
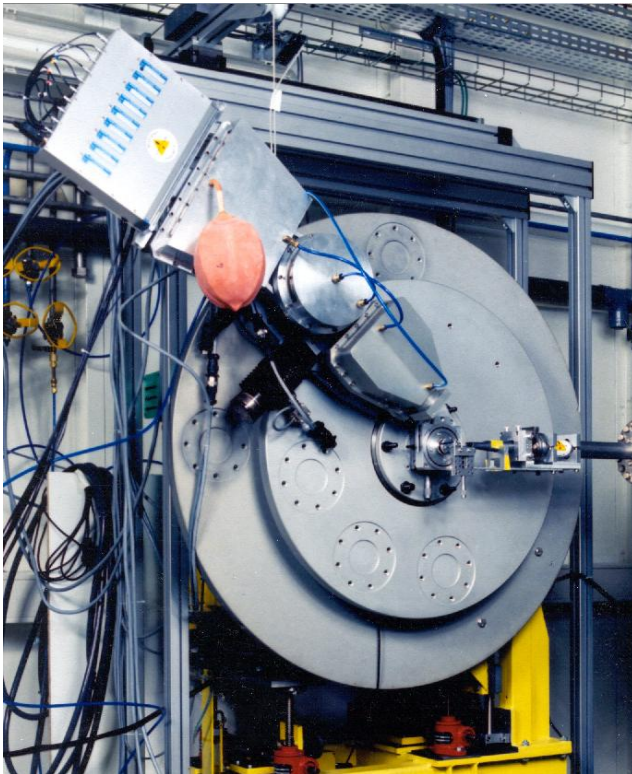


Comparison of APD to YAP and NaI scintillator.

	NaI(Tl)	YAP:Ce	APD
Active area	5cm ²	5cm ²	0.15 -1cm ²
Energy range	5keV...	5...60keV	3...30keV
Energy resolution @ 22keV	28%	56%	20-30%
Dynamic with dead time correction	400Khz	3Mhz	50Mhz
Dead time	1μs	0.11μs	0.006 μs
Linearity @ 1% dead time	10K	100khz	2Mhz
Linearity @ 5% dead time	50K	450khz	9Mhz

beamline I D31

semitransparent
9 APD array

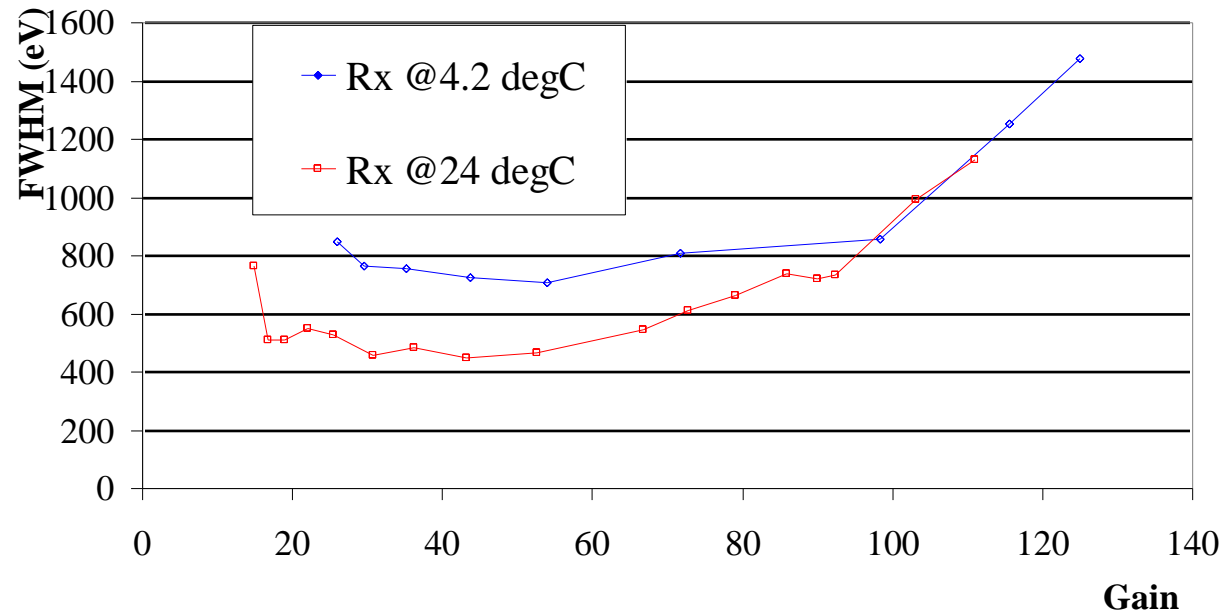


ESRF beamline I D31 (A Fitch)

Nine-channel multianalyser stage: J.-L. Hodeau, M. Anne, P. Bordet, A. Prat, CNRS-Grenoble.

...Resolution...

C30626 , Fe-55 source (Mn K_{α} , at 5.9, 6.4keV)

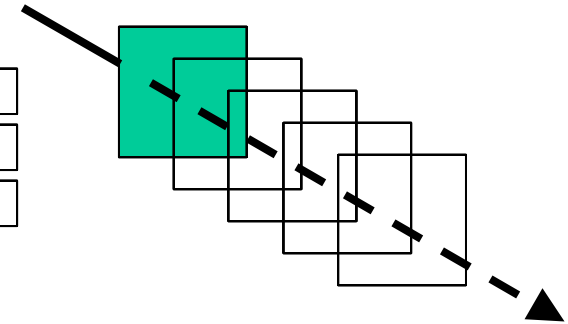
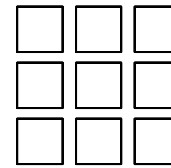
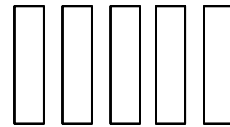


Resolution is dependent upon

- Fano statistics of photon absorption (\sim photon energy^{1/2})
- Multiplication noise (\sim APD internal gain²)
- preamplifier noise (\sim bandwidth^{1/2})

Future?

- APD arrays and telescopes



- custom head packaging (vacuum, cryogenic...?)
- faster counting --> 350 MHz 'ESRF machine limit'